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DiATOME Diamond Knives



unsurpassed & unmatched...

Ultra-Wet 35° • Ultra-Dry 35°
 Ultra-Semi 35° • Ultra Maxi 35°
 Ultra Jumbo 35° • Ultra Sonic 35°
 Ultra ATS 35° Ultra-AFM 35°
 Ultra-Wet 45° • Ultra Jumbo 45°
 Cryo 25° • Cryo Immuno 35°
 Cryo-Dry 35° • Cryo-Wet 35°
 Cryo-Dry 45° • Cryo-Wet 45° Cryo-AFM
 Histo 45° • Histo Jumbo 45°
 Histo-Cryo Dry 45° • Histo-Cryo Wet 45°
 Trimtool 20 • Trimtool 45 • Static Line II



for more information, please
 visit our website at...

www.emsdiasum.com

DiATOME U.S.

P.O. Box 550 • 1560 Industry Rd.
 Hatfield, PA 19440
Tel: (215) 412-8390
Fax: (215) 412-8450
email: info@emsdiasum.com
 or stacie@ems-secure.com

Need a bigger boat?...

DiATOME is still innovating. We are
 pleased to announce these latest
 additions to our line...

NEW ultra Maxi

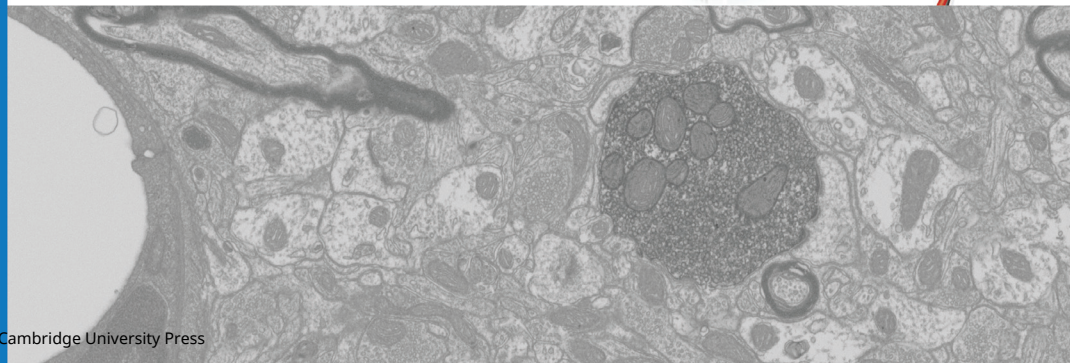
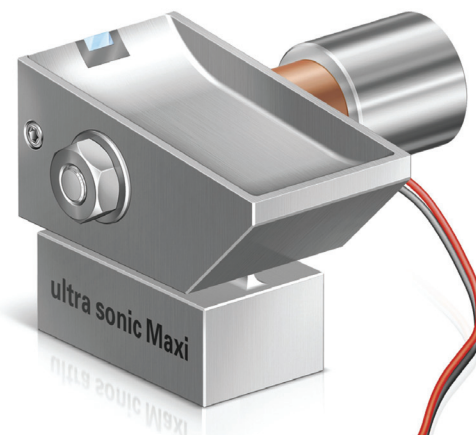
The ultra Maxi is similar to our ultra 35°
 4.0 mm but with a larger boat.
 Thickness range: 30-200nm



NEW ultra sonic Maxi

The ultra sonic Maxi is a new wider
 ultra sonic knife specifically for
 compression-free serial sectioning
 in biological applications. The knife
 comes in 3.0mm and 4.0mm sizes
 with 35° angle.

Biocytin-labeled giant bouton from the auditory cortex of a
 Mongolian gerbil acquired with a scanning electron microscope.
 Saldeitis et al., 2019 Eur. J. Neurosci. Vol.50-9:3445-3453.



ETHOS

Focused Ion and Electron Beam System

HITACHI
Inspire the Next



...Aspire to Excellence

The Hitachi ETHOS SEM-FIB combines ultra-high resolution imaging and elemental analysis at low voltages with ion optics for nm-scale precision processing.

Designed with a variety of applications in mind

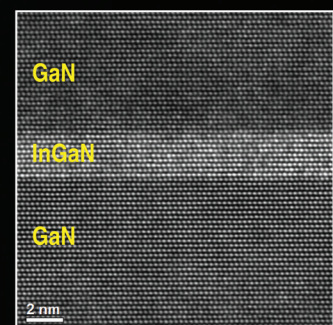
- Large analytical specimen chamber for numerous accessories
- Automated operation including macro processing
- Time sharing mode for dual simultaneous live imaging and processing
- Real-time analytical 3D segmentation capability

Advanced Microsampling

- Sample orientation control with Anti Curtaining Effect (ACE) technologies
- 4-axis lift-out function for advanced TEM specimen preparation

Triple-beam system yielding highest-quality results

- Low acceleration voltage processing with noble gas ion beam
- Selectable ion species (argon/xenon)



200 kv ADF STEM Image of processed lamella by Triple Beam Ar Ion at 1kV

For more information, visit www.hitachi-hightech.com/us/fib

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